

66/01/99
JC559 U.S. PTO

Please type a plus sign (+) inside this box → ☒

PTO/SB/50 (4/98)
Approved for use through 09/30/2000. OMB 0651-0033
Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE
Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it displays a valid OMB control number.

A/KC
JC525 U.S. PTO
09/324098
66/10/99

REISSUE PATENT APPLICATION TRANSMITTAL

Address to: Assistant Commissioner for Patents Box Patent Application Washington, DC 20231	Attorney Docket No.	140-035
	First Named Inventor	James P. Reilly
	Original Patent Number	5,712,479
	Original Patent Issue Date (Month/Day/Year)	January 27, 1998
	Express Mail Label No.	FX362058406US

APPLICATION FOR REISSUE OF: ☒ Utility Patent ☐ Design Patent ☐ Plant Patent
(check applicable box)

APPLICATION ELEMENTS	ACCOMPANYING APPLICATION PARTS
1. <input checked="" type="checkbox"/> * Fee Transmittal Form (PTO/SB/56) (Submit an original, and a duplicate for fee processing)	7. <input type="checkbox"/> Foreign Priority Claim (35 U.S.C. 119) (if applicable)
2. <input checked="" type="checkbox"/> Specification and Claims (amended, if appropriate)	8. <input type="checkbox"/> Information Disclosure Statement (IDS)/PTO-1449 <input type="checkbox"/> Copies of IDS Citations
3. <input checked="" type="checkbox"/> Drawing(s) (proposed amendments, if appropriate)	9. <input type="checkbox"/> English Translation of Reissue Oath/Declaration (if applicable)
4. <input checked="" type="checkbox"/> Reissue Oath / Declaration (original or copy) (37 C.F.R. § 1.175)(PTO/SB/51 or 52)	10. <input type="checkbox"/> * Small Entity Statement filed in prior application, Status still proper and desired (PTO/SB/09-12)
5. Original U.S. Patent <input checked="" type="checkbox"/> Offer to Surrender Original Patent (37 C.F.R. § 1.178) (PTO/SB/53 or PTO/SB/54) or <input type="checkbox"/> Ribboned Original Patent Grant <input type="checkbox"/> Affidavit / Declaration of Loss (PTO/SB/55)	11. <input type="checkbox"/> Preliminary Amendment
6. Original U.S. Patent currently assigned? <input checked="" type="checkbox"/> Yes <input type="checkbox"/> No (If Yes, check applicable box(es)) <input type="checkbox"/> Written Consent of all Assignees (PTO/SB/53 or 54) <input type="checkbox"/> 37 C.F.R. § 3.73(b) Statement <input type="checkbox"/> Power of Attorney	12. <input checked="" type="checkbox"/> Return Receipt Postcard (MPEP 503) (Should be specifically itemized)
	13. <input type="checkbox"/> Other:

*** NOTE FOR ITEMS 1 & 10: IN ORDER TO BE ENTITLED TO PAY SMALL ENTITY FEES, A SMALL ENTITY STATEMENT IS REQUIRED (37 C.F.R. § 1.27), EXCEPT IF ONE FILED IN A PRIOR APPLICATION IS RELIED UPON (37 C.F.R. § 1.28).**

14. CORRESPONDENCE ADDRESS

<input type="checkbox"/> Customer Number or Bar Code Label	(Insert Customer No. or Attach bar code label here)	or <input checked="" type="checkbox"/> Correspondence address below
Name	Ward & Olivo	
Address	708 Third Avenue	
City	New York	State NY Zip Code
Country	USA	Telephone (212) 697-6262 Fax (212) 972-5866

NAME (Print/Type)	John F. Ward	Registration No. (Attorney/Agent)	33,811
Signature	<i>John F. Ward</i>	Date	June 1, 1999

Burden Hour Statement: This form is estimated to take 0.2 hours to complete. Time will vary depending upon the needs of the individual case. Any comments on the amount of time you are required to complete this form should be sent to the Chief Information Officer, Patent and Trademark Office, Washington, DC 20231. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Assistant Commissioner for Patents, Box Patent Application, Washington, DC 20231.

1
SPATIAL-VELOCITY CORRELATION
FOCUSING IN TIME-OF-FLIGHT MASS
SPECTROMETRY

CROSS-REFERENCE TO RELATED
APPLICATIONS

This application is a continuation of U.S. patent application Ser. No. 08/327,618, filed Oct. 24, 1994, now U.S. Pat. No. 5,504,326, which issued Apr. 2, 1996.

FIELD OF THE INVENTION

The present invention relates to instrumentation for providing molecular mass spectral information using time-of-flight measurement methods, and more specifically to an apparatus and method for improving the resolution of such instrumentation by simultaneously reducing the effect of both the initial spatial and initial velocity distributions of the ionized molecules.

BACKGROUND OF THE INVENTION

Instrumentation for performing time-of-flight (TOF) mass spectral analysis to determine the mass of an ionized molecule has been known for several decades. By measuring the velocity (v) of an ion having a known kinetic energy (KE), its mass (m) can be determined via the well known relationship:

$$KE = \frac{mv^2}{2} \quad (1)$$

A typical two-step linear time-of-flight mass spectrometer 10 (TOFMS) shown in FIG. 1 has three distinct regions. For gas phase sample sources, the gas circulates within region 1 of width d_1 , located between grids (or plates) G_0 12 and G_1 16. Within region 1, ions 24 and 26 are produced from the sample using, for example, an electron beam or a laser. Ions 24 and 26 are ideally formed at a position X_0 and then accelerated to the same kinetic energy by electric fields E_1 , generated within region 1, and E_2 , generated within region 2, where region 2 is of width d_2 and is located between grids (or plates) G_1 16 and G_2 18. Electric field E_1 is achieved in the direction shown in FIG. 1 to accelerate positively charged ions by applying appropriate voltage potentials to the grids (or plates) G_0 12 and G_1 16. Similarly, electric field E_2 is achieved in the direction shown to accelerate positively charged ions by applying appropriate voltage potentials to the grids (or plates) G_1 16 and G_2 18. It should be noted that electric fields E_1 and E_2 may be reversed in direction, by applying voltage potentials of appropriate magnitudes to grids (or plates) G_0 12, G_1 16 and G_2 18, to accelerate negatively charged ions to the same kinetic energy in the direction shown in FIG. 1.

Within the field free drift region 20 of length L , ions with different mass to charge ratios separate in space and time. For example, if ion 24 has mass m_1 and ion 26 has mass m_2 , where m_2 is greater than m_1 , then ion 24 will reach the end 22 of the drift region 20 before ion 26. A detector 28 is typically located at the end 22 of the drift region 20 for recording the arrival of ions as a function of time. Thus, the difference between the start time, common to all ions generated within region 1, and the arrival time, at the detector 28, of a packet of ions having the same mass is a function of their mass to charge ratio (m/z), and can therefore be used to calculate the mass of the ions.

If an ion's flight time was strictly dependent upon its mass-to-charge ratio, the TOFMS 10 (or any other TOFMS

In FIG. 3, an example is shown where two ions 34 and 36 have identical masses and begin their acceleration toward the end 22 of the drift region 20 at the same distance X_0 from grid G_0 12, but have different initial velocities as shown by the magnitudes of the arrows extending therefrom. Since both ions 34 and 36 experience the same acceleration in electric fields E_1 and E_2 , the total velocity of ion 36 will always be greater than that of ion 34 and it will therefore reach the end 22 of the drift region 20 before ion 34. As with the initial spatial differential example shown in FIG. 2, a difference in total velocity between ions 34 and 36, in this case due to different initial velocities, results in a variation

in measured time of flight, and decreased TOFMS 10 resolution, of this particular ion signal.

In the TOFMS 10 of FIGS 1-3, ions are formed from a gas phase sample circulating within region 1, typically by electron impact ionization or laser induced ionization. Ions so formed have a spatial distribution that is independent of their velocity distribution. In contrast, ions can also be produced in the source region (region 1) of TOFMS 10 from involatile molecules, i.e., those that remain on a surface until being desorbed into the gas phase by laser irradiation, particle bombardment or similar means. Desorption may produce neutral molecules (neutrals) for later ionization in the gas phase, and/or may produce gas phase ions directly from the sample surface. The instant of time t_0 at which either desorbed neutrals are converted into ions in an electric field or, alternatively, the instant of time at which desorbed ions are accelerated toward a detector by a pulsed electric field (hereinafter referred to as an ion drawout electric field), provides the starting point for measuring ion flight times to the detector. In either case, the spatial and velocity distributions of ions at t_0 are referred to as the initial spatial and velocity distributions. Following the drawout of ions by either technique, ion flight through a TOFMS, such as TOFMS 10, occurs in the same manner as described with respect to FIG. 1.

Referring now to FIG. 4, a sample 14 is deposited onto grid (or plate) G_0 12 of TOFMS 10 for desorption of ions therefrom. With this approach, initial ion velocity distribution is a principal contributor to mass spectral peak broadening. When ions are desorbed/ionized from such a sample 14, their velocity distribution, as shown by arrows 38 and 40, is typically wider than those observed with gas phase samples. This is because of the energy required to induce the desorption, and results in further broadening of the mass spectral peaks and corresponding reduction in TOFMS 10 resolution.

Over the past several decades, many techniques have been developed to increase mass resolution in the TOFMS by compensating for the initial variations in ion velocity and position. Two noteworthy examples are the space focusing technique disclosed in U.S. Pat. No. 2,685,035 to Wiley and in *Time-of-Flight Mass Spectrometer with Improved Resolution*, Wiley, W. C. and McLaren, I. H., Rev. Sci. Instr. 26, 1150 (1955), and the development of a reflectron TOFMS as disclosed in *The Mass-Reflectron, A New Non-magnetic Time-of-Flight Mass Spectrometer With High Resolution*, Mamyrin, B. A., Karataev, V. L., Shmikk, D. V. and Zagulin, V. A., Sov. Phys. JETP 37, 45 (1973).

Using the space focusing technique, an equation for total distances of the various regions in the TOFMS (D_n) and the ion flight time is derived. The time of flight (TOF) is a function of the ion's mass to charge ratio (m/z), initial position (X_0) and initial velocity (v_0), the total strengths of the various electric fields established within the TOFMS (E_n). In other words,

$$\text{TOF} = f(m/z, X_0, v_0, D_n, E_n) \quad (2)$$

The partial derivative of equation (2) is taken with respect to X_0 , set equal to zero and solved for E_n . This technique results in finding a set of grid voltages that establish the necessary electric fields for minimizing the effect of the initial variations in ion position. Although the corollary "velocity focusing" cannot be implemented (i.e., a set of practical electric fields that yield the result $\partial \text{TOF} / \partial v_0 = 0$ cannot be found), Wiley and McLaren further attempted to

correct for the initial velocity distribution by providing a time delay between the formation and acceleration of the ions (called time lag focusing). They noted, however, that their initial spatial and velocity distributions are independent, and that time lag focusing necessarily violates space focusing conditions. Thus, depending on which distribution contributes more to mass spectral peak broadening, they concluded that time lag focusing may improve spectrometer resolution in some cases, but in other cases it will have a defocusing effect.

In the reflectron TOFMS, an ion mirror is placed in the flight path of the ion packets. If the mirror electrode voltages are arranged appropriately, the peak width contribution from the initial velocity distribution can be significantly reduced at the plane of the detector. In operation, the structural arrangement of the reflectron TOFMS requires ions produced with large velocities to travel greater distances than their slower counterparts, leading to narrowed temporal profiles at the detector. Such an instrument, however, is significantly more complicated than a linear TOFMS and still suffers from the initial ion spatial distribution discussed above.

In recent years, the formation of ions within a typical TOFMS has been routinely accomplished by direct desorption from a sample surface as previously discussed. Lasers ranging in wavelength from the far-UV to the far-IR have been used with a variety of organic and inorganic materials to generate ions for analysis by mass spectrometry, leading to the development and commercial availability of the laser microprobe mass analyzer (LAMMA) and the laser ionization mass analyzer (LIMA). Although widespread in use, these instruments were somewhat limited. Only atoms or molecules below a particular size could be desorbed either as intact ions or as intact neutrals that could be subsequently ionized in the gas phase. In the last few years, however, the ability to produce gas phase ions of large biomolecules and polymers was developed using a technique known as matrix-assisted laser desorption/ionization (MALDI). In addition to laser desorption, other ion formation techniques are known, such as fast atom bombardment (FAB), plasma desorption (PD) and the desorption of secondary ions from surfaces using primary ions in the keV energy region. The latter has led to the development of the secondary ion mass spectrometer (SIMS).

The recent popularity of MALDI has led to the modification of TOFMS 10 shown in FIG. 5. Since mass spectral peak broadening is believed to be dominated by the initial ion velocity distribution in desorption/ionization techniques, researchers have attempted to reduce its effect by using high ion drift energies. In what will hereinafter be referred to as the "traditional MALDI technique", ions generated within region 1 are accelerated to high velocities (to reduce the effect of initial ion velocity distribution on total velocity within the drift region) and then allowed to travel through the drift region 20 of increased length to a detector 110 located at the end 22 of the drift region 20. Thus, although "velocity focusing" per se cannot be performed, the effects of initial ion velocity distribution on mass spectral peak broadening can be reduced by using high drift velocities. This approach requires only a single acceleration region. A schematic of such an instrument 11 is shown in FIG. 5 wherein G_2 18 of TOFMS 10 in FIG. 4 has been removed and the drift region 20 is extended to length L' .

Regardless of the ion formation method, each of the foregoing techniques and instruments is used with time-of-flight analysis in generating mass spectra. Thus, all suffer from the resolution limiting factors discussed above.

Therefore, what is needed is a simple and effective technique for either eliminating or drastically reducing the effects of these distributions in a linear TOFMS in order to increase mass spectral resolution in such an instrument.

SUMMARY OF THE INVENTION

The present invention provides a solution to the foregoing problems and shortcomings of the prior art techniques for increasing the mass resolution of a time-of-flight mass spectrometer.

According to one aspect of the present invention, a method of spatial-velocity correlation focusing in a time-of-flight mass spectrometer to minimize the effects of distributions in initial ion position and initial ion velocity on the ion mass resolution of the spectrometer is provided. The spectrometer has a first region for applying an ion accelerating field to accelerate ions of various mass to charge ratios generated from a sample source disposed within the first region and an ion detector remote from the first region. The method comprises the steps of (1) determining a first equation for the time-of-flight of the ions generated within the first region to the detector. The first equation depends upon the internal geometry of the spectrometer and is a function of a set of spectrometer variables including ion acceleration field strengths, distance between the generated ions and the detector, ion mass, initial position of the ions generated within the first region, initial velocity of the ions generated within the first region and the time delay between the generation of ions within the first region and application of the acceleration field for accelerating the ions toward the detector, (2) determining a second equation relating initial ion position within the first region to initial ion velocity within the first region. The second equation depends upon the location of the sample source within the first region and is a function of the ion generation geometry, (3) substituting the second equation into the first equation to form a third equation for the time-of-flight of ions from the first region of the spectrometer to the detector. The third equation eliminates one of the initial ion position and the initial ion velocity as a variable thereof, and (4) determining the optimum set of variables from the third equation so that the time spread in the time-of-flight of generated ions of any particular mass to charge ratio to the detector is minimized, wherein minimizing the time spread in the time-of-flight of the generated ions to the detector of any particular mass to charge ratios results in minimizing the effects of both the initial ion position distribution and initial ion velocity distribution on the ion mass resolution of the spectrometer.

According to another aspect of the present invention, a time-of-flight mass spectrometer (TOFMS) for minimizing the effect on the TOFMS mass resolution of distributions in initial position and initial velocity of ions generated within the spectrometer is provided. The TOFMS comprises a first grid connected to a first potential source for applying a first potential thereto, a second grid juxtaposed with the first grid, the first and second grids defining a first region therebetween, the second grid being connected to a second potential source for applying a second potential thereto, a sample source disposed within the first region for generating ions of various mass to charge ratios therefrom into the first region when the sample source is excited by external means, wherein the ions have an initial position distribution and an initial velocity distribution within the first region, and the initial position of each of the ions is a function of the initial velocity of the respective ion, and means for detecting the ions generated within the first region, the means for detecting being disposed remote from the second grid. The first

and second potentials are applied to the first and second grids respectively at a predetermined time after the ions are generated within the first region to establish a first electric field of appropriate direction for accelerating the ions toward the means for detecting. The relative strengths of the first and second potentials and the predetermined time at which they are applied to the grids are chosen so that the time spread in the time of flight of ions of any particular mass to charge ratio generated within the first region to the means for detecting is minimized, thereby simultaneously minimizing the effect on the TOFMS mass resolution of the distributions in initial position and initial velocity of the ions generated within the first region.

According to a further aspect of the present invention, a system for minimizing the effect of distributions in initial ion position and initial velocity on the mass resolution of a time-of-flight mass spectrometer (TOFMS) is provided. The system comprises a TOFMS having a sample source disposed within a sample region and an ion detector disposed a predetermined distance from the sample source, means for generating ions of various mass to charge ratios from the sample source, wherein the generated ions have an initial position distribution and an initial velocity distribution within the sample region, and the initial position of each of the ions generated within the sample region is a function of the initial velocity of the respective ion, means for establishing an electric field within the sample region of the TOFMS, the electric field accelerating the generated ions toward the ion detector, and means responsive to the ion generating means for triggering the electric field establishing means to establish the electric field a predetermined time after generating the ions. The strength of the electric field and the predetermined time period are chosen so that the time spread in the time of flight of generated ions of any particular mass to charge ratio to the means for detecting is minimized, thereby simultaneously minimizing the effect on the TOFMS mass resolution of the distributions in initial position and initial velocity of the generated ions.

It is one object of the present invention to provide a method for simultaneously minimizing the effect of initial ion spatial distributions and initial ion velocity distributions on the mass resolution of a time-of-flight mass spectrometer.

It is another object of the present invention to provide a system for simultaneously minimizing the effect of initial ion spatial distributions and initial ion velocity distributions on the mass resolution of a time-of-flight mass spectrometer.

These and other objects of the present invention will become more apparent from the following description of the preferred embodiment.

BRIEF DESCRIPTION OF THE DRAWINGS

FIG. 1 is a schematic diagram of a typical two-stage linear time-of-flight mass spectrometer (TOFMS) of the prior art.

FIG. 2 is a schematic diagram of the TOFMS of FIG. 1 illustrating the effect on flight time of a spatial distribution in the generated ions.

FIG. 3 is a schematic diagram of the TOFMS of FIG. 1 illustrating the effect on flight time of a velocity distribution in the generated ions.

FIG. 4 is a schematic diagram of the TOFMS of FIG. 1 illustrating the effect on ion flight time of a velocity distribution in ions generated from a sample surface.

FIG. 5 is a schematic diagram of a modified TOFMS of FIG. 4 illustrating a known technique for reducing the effect of a velocity distribution in ions generated from a sample surface on TOFMS mass resolution.

FIG. 6 is a cross-sectional diagrammatic illustration of a TOFMS in accordance with the present invention

FIG. 7 is a schematic diagram of the ion formation portion of the TOFMS of FIG. 6 showing the relationship between initial ion position and initial ion velocity.

FIG. 8 is a schematic diagram of the ion formation portion of a TOFMS having an alternate ion generating geometry.

FIG. 9 is a schematic diagram of the ion formation portion of a TOFMS having another alternate ion generating geometry.

FIG. 10 is a block diagrammatic illustration of a system for performing spatial-velocity correlation focusing with a linear TOFMS in accordance with the present invention.

FIG. 11 is a flow chart of a method for determining spatial-velocity correlation focusing conditions for use with a linear TOFMS in accordance with the present invention.

FIG. 12 is an experimental MALDI-TOF mass spectrum of Insulin obtained using traditional MALDI techniques.

FIG. 13 is an experimental MALDI-TOF mass spectrum of Cytochrome-c obtained using traditional MALDI techniques.

FIG. 14 is an experimental MALDI-TOF mass spectrum of Lysozyme obtained using traditional MALDI techniques.

FIG. 15 is an experimental MALDI-TOF mass spectrum of Trypsinogen obtained using traditional MALDI techniques.

FIG. 16 is an experimental MALDI-TOF mass spectrum of Insulin obtained using spatial-velocity correlation focusing conditions in accordance with the present invention.

FIG. 17 is an experimental MALDI-TOF mass spectrum of Cytochrome-c obtained using spatial-velocity correlation focusing conditions in accordance with the present invention.

FIG. 18 is an experimental MALDI-TOF mass spectrum of Lysozyme obtained using spatial-velocity correlation focusing conditions in accordance with the present invention.

FIG. 19 is an experimental MALDI-TOF mass spectrum of Trypsinogen obtained using spatial-velocity correlation focusing conditions in accordance with the present invention.

DESCRIPTION OF THE PREFERRED EMBODIMENT

For the purposes of promoting an understanding of the principles of the invention, reference will now be made to the embodiment illustrated in the drawings and specific language will be used to describe the same. It will nevertheless be understood that no limitation of the scope of the invention is thereby intended, such alterations and further modifications in the illustrated device, and such further applications of the principles of the invention as illustrated therein being contemplated as would normally occur to one skilled in the art to which the invention relates.

Referring now to FIG. 6, a time-of-flight mass spectrometer (TOFMS) 100 for spatial-velocity correlation focusing in accordance with the present invention is shown in cross-section. As will be more fully explained hereinafter, power sources 122 and 124, and voltage pulser 128 are actuated with specific timing and magnitudes, depending on the internal geometry of the TOFMS 100 and the ion generation geometry, to simultaneously minimize the effects of the initial position distribution and initial velocity distribution of the generated ions on the mass resolution of the TOFMS.

In a preferred embodiment, power sources 122, 124, 126, and 129 are DC high voltage power supplies. Alternatively, supplies 122, 124, 126, and 129 may supply time dependent voltages that optimally modify the spatial and velocity distributions of the ions before application of the output from voltage pulser 128. Careful selection of these and other TOFMS parameters significantly reduces the mass spectral peak broadening due to the two distributions.

Voltage plate 102 and voltage grid 106 are arranged in a juxtaposed relationship and define a first region 108 therebetween. Region 108 has length d_1 and contains the sample source 104. Although sample source 104 is shown as being located within a groove of voltage plate 102 so that the surface of the sample source 104 is coextensive with the surface of plate 102, the present invention contemplates locating sample source 104 at a variety of locations within region 108 as will be subsequently explained with reference to FIGS. 7-9.

In a preferred embodiment, sample source 104 is a stainless steel surface with the sample deposited thereon. Alternatively, sample source 104 may be a conductive metal grid, a dielectric surface with or without a thin metallic film coating or a comparable structure having an orifice through which sample molecules flow.

In a preferred embodiment, voltage plate 102 is a flat, highly conductive, metallic plate having a groove through the center of its surface for receiving the sample source 104. Voltage grid 113 is juxtaposed with voltage grid 106 and a second region 110 of length d_2 is defined therebetween. A flight tube 112 is connected between voltage grid 113 and grid 115. Flight tube 112 is constructed of a conducting material, typically aluminum, and has a channel 114 disposed therethrough which defines an ion drift region of length L . Ion detector 116 is juxtaposed with the grid 115 of flight tube 112 and a third region of length d_3 is defined between grid 115 and surface 117 of detector 116. In a preferred embodiment, detector 116 is a tandem microchannel plate array detector. Supports 134 and 136 are used to stabilize flight tube 112 and voltage plate 102 respectively within the TOFMS 100, and are preferably made of Teflon™. In one embodiment, grids 106, 113 and 115 are constructed of high conductivity metal having slits or apertures disposed therethrough so that ions may pass through. In an alternative embodiment, grids 106, 113 and 115 comprise high conductivity metallic plates having a central hole, or a series of holes disposed through the center, for allowing the passage of ions.

A first DC power source 122 is connected to voltage plate 102 for supplying a predetermined DC voltage potential V_0 thereto and a second DC power source 124 is connected to voltage grid 106 for supplying another predetermined DC voltage potential V_2 thereto. Although V_0 and V_2 may be widely varied, such as within the range of ± 30 kV for example, both plate 102 and grid 106 are typically maintained at the same voltage, and in one embodiment, this voltage is 15 kV. A first voltage pulser 128 is connected to the first DC power supply 122 and also through a capacitor C_1 to voltage plate 102 for supplying a predetermined duration voltage pulse to plate 102 of a predetermined amplitude. In a preferred mode of operation, voltage pulser 128 supplies a voltage pulse V_p to voltage plate 102 so that the total voltage present at plate 102 V_1 is the sum of the DC voltage V_0 and the voltage pulse V_p , thereby establishing an electric field E_1 of predetermined strength within the first region 108 for the duration of the pulse. In an alternate embodiment, the output of voltage pulser 128 may be used to change the electric field that had previously been estab-

lished across region 108 by power sources 122 and 124. Voltage pulser 128 may further be connected to grid 106 instead of plate 102. Alternatively, any known method of establishing an electric field E_1 within region 108, of sufficient magnitude and duration, may be used. This electric field E_1 established within the first region 108 acts to accelerate positively charged ions present within the region 108 toward the ion detector 116. As previously stated, the electric field E_1 could be reversed to accelerate negatively charged ions toward the detector 116,

A third DC power source 126 is connected to voltage grid 113 for supplying a predetermined DC voltage potential V_3 thereto. Although the voltage V_3 on grid 113 may also be widely varied, such as within the range of ± 30 kV for example, this voltage is, in operation, maintained below the voltage on grid 106 so that a second electric field E_2 is established within region 110 for further accelerating positively charged ions entering region 110 toward the detector 116. In one embodiment, the voltage on grid 113 is maintained at approximately 12 kV.

A fourth DC power source 129 and a second voltage pulser 130 are connected to the detector 116. In operation, the fourth DC power source 129 supplies a constant potential V_4 to the detector 116 of sufficient magnitude to establish an electric field E_3 for further accelerating ions entering region 118 toward the detector 116. Although the voltage V_4 on the detector 116 may be widely varied, such as within the range of ± 30 kV for example, V_4 is typically set at approximately -1.4 kV. In one embodiment, voltage pulser 130, capacitively coupled to the detector 116 through a capacitor C_2 , supplies a voltage pulse to the detector 116 to increase the gain of the detector 116 for the duration of the pulse to facilitate data capture. In alternative embodiments, other known methods of momentarily increasing the gain of the detector 116 may be used to enhance data capture or data capture may be enhanced by preventing, through the use of pulsed ion deflectors, unwanted ions from reaching the detector.

Finally, a laser 132 is focused on the sample source 104 for generating ions therefrom. Typically, the laser is pulsed and it is assumed that ions are desorbed from the sample source 104 upon being subjected to the laser radiation pulse. Although a laser 132 is used to generate the ions in a preferred embodiment, the present invention may be used with systems employing other ion generation methods as well, including, for example, fast atom bombardment (FAB), plasma desorption (PD), secondary ion generation such as that used in secondary ion mass spectrometry (SIMS), electron bombardment and the like.

Ion time-of-flight within a TOFMS, such as TOFMS 100, is typically mathematically modeled by breaking down the flight path into a series of segments, determining the ion flight time within each segment, and then summing the flight times of the various segments to arrive at a total ion flight time. A variable number of segments may be used to mathematically model the flight time in a time-of-flight instrument. In the example that follows, the TOFMS 100 flight path is broken down into four segments corresponding to regions 108, 110, 114 and 118. Alternatively, for example, region 118 could be further broken down into region 121, extending between grid 115 and the dotted line 119, and region 120, extending between the dotted line 119 and the surface 117 of the detector 116, in which case the flight path would have five segments.

Using the four segment approach, in a preferred embodiment where power supplies 122, 124, 126, and 129 provide

DC voltages, the flight time t_1 of ions within region 108 is a function of the component of the initial ion velocity along the flight tube axis (parallel to the electric fields E_1-E_3) v_0 , the velocity of the ions leaving region 108 v_1 and the acceleration strength a_1 of the electric field E_1 established within region 108. Thus

$$t_1 = (v_1 - v_0) / a_1 \quad (3)$$

If X_0 is the position of a particular ion generated from the sample source 104, then

$$v_1 = \sqrt{2a_1(d_1 - X_0) + v_0^2} \quad (4)$$

Similarly, the flight time t_2 of ions within region 110 is a function of the velocity of ions entering region 110 v_1 , the velocity of ions leaving region 110 v_2 and the acceleration strength of the electric field E_2 established within region 110. Thus,

$$t_2 = (v_2 - v_1) / a_2 \quad (5)$$

where

$$v_2 = \sqrt{2a_2d_2 + v_1^2} \quad (6)$$

Furthermore, the flight time t_3 of ions within region 118 is a function of the velocity of ions entering region 118 v_2 , the velocity of ions leaving region 118 v_3 and the acceleration strength a_3 of the electric field E_3 established within region 118. Thus,

$$t_3 = (v_3 - v_2) / a_3 \quad (7)$$

where

$$v_3 = \sqrt{2a_3d_3 + v_2^2} \quad (8)$$

Finally, since region 114 is an electric field free ion drift region, the ion flight time t_4 is a function only of the ion velocity v_3 through region 114 and the length L of region 114. Thus,

$$t_4 = L / v_3 \quad (9)$$

Since the total ion flight time within the TOFMS 100 is the sum of the four flight time segments, the equation for the total flight time T within TOFMS 100 is

$$T = f(a_1, a_2, a_3, d_1, d_2, d_3, L, X_0, v_0) \quad (10)$$

Using equation (10), the limitations of the prior art space focusing technique described in the background section can be readily understood. In implementing the space focusing technique, the initial ion position and initial ion velocity are independent variables and the derivative of equation (10) is taken with respect to initial ion position X_0 , which leads to

$$\frac{\partial T}{\partial X_0} = -\frac{1}{v_1} + \frac{a_1}{a_2} \left(\frac{1}{v_1} - \frac{1}{v_2} \right) + \frac{a_1}{a_3} \left(\frac{1}{v_2} - \frac{1}{v_3} \right) + \frac{a_1 L}{v_3^2} \quad (11)$$

Setting equation (11) equal to zero, and recognizing that the acceleration terms a_x are related to the voltage potential values on plate 102 and grids 106 and 113 and detector 116 via the well known relationships

$$c_s = qE_1/m \quad (12)$$

and

$$E_x = (V_1 - V_2)/d_x \quad (13)$$

where m is ion mass and q is ion charge, the ratio of electric fields E_x can be determined. By choosing a value for a further parameter, such as a desired ion velocity within the ion drift region 114, it is readily observed that the space focusing technique permits only the relatively easy determination of the voltages $V_1 - V_2$, given a selected set of region distances $d_1 - d_2$ and L .

In contrast to the spatial focusing technique discussed above and the techniques discussed in reference to FIG. 5 for reducing the effects of initial ion velocity on mass spectral peak broadening, the present invention takes advantage of the fact that, in many time-of-flight instruments, depending upon the ion generation geometry, initial ion position is a function of initial ion velocity. This functional relationship can be exploited by determining the spatial-velocity correlation for the particular ion source geometry, substituting this correlation into the time-of-flight equation, such as equation (10) for TOFMS 100, to remove either X_0 or v_0 from equation (10), taking the derivative of new equation (10) with respect to the remaining variable (either X_0 or v_0), setting this derivative equal to zero and solving for the optimal instrument parameters. Alternatively, new equation (10) can be employed numerically to identify optimal instrument parameters. This is done by considering variations in all instrument parameters that affect ion time of flight, and searching for those parameters that minimize the spread of flight times with respect to changes in the remaining variable (either X_0 or v_0). In either case, if the initial ion position and initial ion velocity are correlated, the spatial-velocity correlation focusing technique reduces the total number of independent variables and independent distributions, and produces at least one additional adjustable parameter over the spatial focusing technique which, if optimized, results in the simultaneous minimization of the effect on TOFMS mass resolution of the correlated initial ion position and velocity distributions.

Referring now to FIGS. 7-9, the relationship between ion spatial and velocity distributions for three alternative ion source geometries will be described. The relational equations generated by these geometries may be directly substituted into a time-of-flight equation, such as equation (10) for TOFMS 100, to achieve spatial-velocity correlation focusing.

Referring to FIG. 7 specifically, the configuration of FIG. 6 is shown wherein the sample source 104 is disposed upon, or coextensive with, voltage plate 102, and ions are desorbed by laser 132 in a direction perpendicular to voltage grid 106 (parallel with electric field E_1). With the geometry of FIG. 7, initial ion position X_0 within region 108 is related to the initial ion velocity component along the flight tube axis, (i.e. perpendicular to grid 106) v_0 within region 108 by the equation

$$X_0 = \tau v_0 \quad (14)$$

where τ is the delay time between the generation of ions at the sample source 104 and commencement of the pulsed ion drawout electric field E_1 , established via voltages V_1 and V_2 at plate 102 and grid 106, respectively.

Referring to FIG. 8, an alternate ion source geometry is shown where the sample source is disposed within region 108 at a distance X_c from plate 102, and the ions are desorbed by laser 132 in a direction parallel to grid 106 (perpendicular to electric field E_1). With the geometry of FIG. 6, initial ion position within region 108 is related to initial ion velocity component along the flight tube axis v_0 within region 108 by the equation

$$X_0 = X_c + \tau v_0 \quad (15)$$

where τ is again the delay time between the generation of ions at the sample source and commencement of the ion pulsed drawout electric field E_1 , established via voltages V_1 and V_2 at plate 102 and grid 106, respectively.

Referring to FIG. 9, another alternate ion source geometry is shown where the sample source is disposed within region 108 at a distance X_c from plate 102, and the ions continuously flow in a direction parallel to grid 106 (perpendicular to electric field E_1). The distance between the sample source 104 and the point where ion acceleration begins is the distance D . In an alternative embodiment, neutral molecules continuously flow from sample source 104 to a distance D where they are ionized by laser light, electron impact or some other ionization means. With the geometry of FIG. 9, initial ion position within region 108 is related to initial ion velocity component along the flight tube axis v_0 within region 108 by the equation

$$X_0 = X_c + \frac{v_0 D}{\sqrt{v_d^2 - v_0^2}} \quad (16)$$

where v_d is the amplitude of the total velocity of the generated ions. Although equation 16 does not generate the new variable τ , it does effectively eliminate either the velocity or spatial distribution from equation 10 by substitution.

Using equations (10) and (14), an example of the derivative method for performing spatial-velocity correlation focusing with TOFMS 100 of FIG. 6 will be given. First, equation (14) is solved for X_0 and substituted into equation (10), resulting in

$$T = f(a_1, a_2, a_3, d_1, d_2, d_3, L, v_0, \tau) \quad (17)$$

Equation (17) represents the ion time-of-flight within TOFMS 100, independent of the initial positions of the ions generated from the sample source 104. Alternatively, equation (14) could have been substituted directly into equation (10) to achieve an expression for ion time-of-flight within TOFMS 100 that is independent of the initial velocities of the ions generated from the sample source 104. In any event, taking the derivative of equation (17) with respect to initial ion velocity v_0 yields

$$\frac{\partial T}{\partial v_0} = f(a_1, a_2, a_3, d_1, d_2, d_3, L, v_0, \tau) \quad (18)$$

By setting equation (18) equal to zero and solving for τ , the optimal delay time between generating ions from the sample source 104 and commencing the pulsed drawout electric field E_1 can be determined. If the derivative of equation (18) is further taken with respect to initial ion velocity v_0 , and set equal to zero, the optimal voltage V_1 can be obtained for determining the amplitude V_p of the first voltage pulser 128. Utilizing the optimal values for τ and V_p in the operation of TOFMS 100, and optimizing the remaining TOFMS 100

parameters, results in minimizing the time spread of the mass peaks in the TOFMS mass spectra

In the alternate embodiments discussed above, the field E_1 may be non-zero and even time dependent before the time τ when ion drawout occurs. In these cases, numerical optimization of instrument parameters for the purpose of minimizing ion time-of-flight spread and optimizing mass spectral resolution may be preferred.

Referring now to FIG. 10, a system for implementing the foregoing spatial-velocity correlation focusing technique is shown. A TOFMS, such as TOFMS 100, along with the microchannel plate detector 116, are the central components of the system. All four of the DC power sources 122, 124, 126 and 129 shown in FIG. 6 are included in the power supplies 150 block which is connected to TOFMS 100 and detector 116. FIG. 6 should be consulted for specific power supply connections. The power supply block 150 is further connected to voltage pulsers 128 and 130 which are, in turn, connected to TOFMS 100 and detector 116 respectively. FIG. 6 should similarly be consulted for specific connections of these elements.

Laser 132 is, in a preferred embodiment, a Quanta Ray DCR-2 Nd:YAG laser at 1.06 microns, although the present invention contemplates using a variety of laser sources ranging from the far-UV to the far-IR. Radiation from laser 132 is frequency tripled by third harmonic generator 154 before being focused onto the sample source 104 within region 108 of TOFMS 100.

Laser 132 is further connected, either at its Q-switch output or through a photodiode that monitors the laser light pulse, to a delay generator 152 which, in turn is connected to voltage pulsers 128 and 130, and waveform recorder 156. Alternatively, a waveform recorder may be used that can record the entire time period from the desorption light pulse to the arrival of macromolecular ions at the detector. This type of waveform recorder can be triggered directly by the laser. In operation, ion generation is assumed to occur at the time of the laser light pulse, so that the delay time τ determined from equation (18) is measured from the time of the laser pulse. As such, the delay generator 152 is programmed with the optimal delay time τ and is operable to trigger voltage pulser 128 to thereby supply the voltage V_p at the optimal time τ and with the optimal strength. Delay generator 152 further triggers the voltage pulser 130 and waveform recorder 156 at a delayed time after voltage pulser 128 is triggered so that the detector 116 and recorder 156 are properly prepared for receiving data. In a preferred embodiment, delay generator 152 is a Stanford Research Systems Pulse Generator, although other comparable precision delay generators may be used.

Detector 116 is further connected to a signal amplifier 158 which, in turn, is connected to the waveform recorder 156. In preferred embodiment, signal amplifier 158 is a LeCroy VV101ATB amplifier and waveform recorder 156 is a Biomation 6500 waveform recorder, although other comparable amplifiers, recorders, and digitizers may be used.

Finally, the output of the waveform recorder 156 is directed to a computer 160 from which an output 162 can be obtained in a variety of formats, including, for instance, hard copies, screen displays, disk storage, CD ROM storage, and the like. In a preferred embodiment, computer 160 is an IBM compatible personal computer, although a variety of computers may be used, such as any type of personal computer, notebook computer, or lap-top computer, mainframe or network computer.

Referring now to FIG. 11, a flow chart is shown for performing spatial-velocity correlation focusing in a time-

of-flight instrument having an ion source geometry wherein the initial position ion distribution is a function of the initial ion velocity distribution. At step 200, an equation is determined for the time-of-flight of ions within the time-of-flight instrument. The TOF equation is a function of initial ion position X_0 , initial ion velocity v_0 , distances traveled by the ions d , the various voltages applied to the various grids within the time-of-flight instrument for creating ion accelerating electric fields, ion mass and delay time τ between the generation of ions within the instrument and the commencement of ion acceleration. An example of such an equation is given by equation (10) above.

Algorithm execution continues at step 202 where a second equation is determined, from the ion source geometry, relating X_0 to v_0 . At step 204, the second equation is substituted into the TOF equation to eliminate either X_0 or v_0 as a parameter of the TOF equation.

In one embodiment of the present invention, the algorithm continues from step 204 to step 206 where initial values for the parameters of the TOF equation of step 204 are chosen. At step 208, ion times-of-flight are calculated over a predicted range of either X_0 or v_0 , depending on which of these parameters remains in the TOF equation of step 204. Preferably, the predicted range of either X_0 or v_0 has been experimentally determined for the type of time-of-flight instrument being used.

Algorithm execution continues at step 210 where the variations in v_0 of step 208 are entered into the TOF equation of step 204 and the variations in the ion times-of-flight are observed. In a preferred embodiment, the time-of-flight variations are observed graphically. The observed spread in the times-of-flight indicates the magnitude of the ion peak width that can be expected to occur in the experimental mass spectrum. If, at step 212, minimal time spreads are observed, the instrument parameters are saved at step 214 and the algorithm continues at step 216. The time spreads at step 212 are considered to be minimal if an improvement in time spreads is observed over previous calculated time spreads.

If the instrument parameters were saved at step 214, or if the observed time spread was not minimal at step 212, the current instrument operating parameters chosen at step 206 or 218 are examined for possible improvement in the time spread. If no further improvement in the time spread is deemed possible at step 216 by further varying the instrument parameters, or if all possible combinations of parameters have been considered, the algorithm is ended at step 220. If, at step 216, further improvement is expected in the time spread by varying the instrument parameters, the instrument parameters are varied and the algorithm returns to step 208.

In an alternate embodiment of the present invention, the algorithm continues from step 204 at step 222 where initial values for all but three of the parameters of the TOF equation of step 204 are chosen; two desired parameters P1 and P2, and either X_0 or v_0 , depending upon which of these latter two variables are present within the TOF equation. At step 224, the first and second derivatives of the TOF equation of step 204 are taken with respect to either X_0 or v_0 , depending upon which of these variables is present in the TOF equation. At step 226, a value is chosen for X_0 or v_0 , preferably through experimentation. At step 228, the two derivatives are set equal to zero. At step 230, the two simultaneous derivative equations of step 228 are solved for the parameters P1 and P2.

At step 232, the status of a solution to the equations of step 230 is tested. If no solution to the simultaneous equations of step 230 is found, algorithm execution continues at

step 242. If, at step 232, a solution to the simultaneous equations of step 230 is found, the parameters chosen in steps 222 and 230 are entered into the TOF equation of step 204, and the variations in the ion times-of-flight generated by variations in v_0 or X_0 are observed at step 234. The observed spread in the times-of-flight indicates the magnitude of the ion peak width that can be expected to occur in the experimental mass spectrum. If, at step 236, minimal time spreads are observed, the instrument parameters are saved at step 238 and the algorithm continues at step 240. The time spreads at step 236 are considered to be minimal if an improvement in the time spreads is observed over previous calculated time spreads.

If the instrument parameters were saved at step 238, or if the observed time spread was not minimal at step 236, the current instrument operating parameters chosen at steps 222 and 230 are examined for possible improvement in the time spread by varying the instrument parameters at step 240. If no further improvement in the time spread is deemed possible at step 240 by further varying the instrument parameters, or if all possible combinations of parameters have been considered, the algorithm is ended at step 244. If, at step 240, further improvement is expected in the time spread by varying the instrument parameters at step 242, the instrument parameters are varied and the algorithm returns to step 224. In a preferred embodiment, the parameters P1 and P2 are chosen to be the time delay τ and the magnitude of the voltage V_p .

As exemplified by the dashed line from step 218 to step 222, and the dashed line from step 242 to step 206, the two foregoing algorithm embodiments are not necessarily mutually exclusive. In other words, after traversing steps 206-218 of the first algorithm embodiment, the algorithm may continue at step 222 rather than returning to step 208. Similarly, after traversing steps 222-242 of the second algorithm embodiment, the algorithm may continue at step 206 rather than returning to step 224.

With any of the algorithm embodiments discussed above, variation of parameters may be accomplished by considering all combinations of parameters. Alternatively, a variety of optimization methods, such as Simplex optimization, for example, may be employed to guide the selection of parameters. Parameter variation may also be based on operator observation of the calculated spread in TOF, or can be based on experimental results.

EXPERIMENTAL RESULTS

Referring now to FIGS. 12-19, experimental results are shown comparing ion time-of-flight peak widths for Bovine Insulin (m/z 5733), Cytochrome-c (m/z 12,360 da), Lysozyme (m/z 14,306 da) and Trypsinogen (m/z 23,981 da) using MALDI. In these experiments, a TOFMS 100, such as that shown in FIG. 4 was used wherein a 3 ns, 355 nm laser pulse was focused onto the sample spot with a 15 cm focal length spherical lens at an incidence angle of approximately 80 degrees from the flight axis. Power densities were on the order of 1-5 MW/cm² and pressure in the TOFMS was approximately 1×10^{-6} torr.

Sample preparation consisted of dissolving the proteins in distilled deionized water to concentrations of 1.67×10^{-4} M. The ferulic acid matrix was dissolved in neat ethanol to a concentration of 0.125M. A sample solution was obtained by mixing three parts protein stock solution with two parts matrix solution. The final concentrations were approximately 1×10^{-4} M and 50 mM for the protein and matrix, respectively. Aliquots of the sample solution (5 microliters) were then deposited on a stainless steel probe (sample source 104) and allowed to air dry before insertion into the TOFMS 100.

FIGS. 12-15 display ion intensity versus time-of-flight data generated for the Insulin sample, Cytochrome-c sample, Lysozyme sample, and Trypsinogen sample, respectively, using traditional MALDI techniques wherein the TOFMS 100 was configured similar to the TOFMS 10 shown in FIG. 5. For the spectra of FIGS. 12-15, V_1 and V_3 were approximately 30 kV and 0 V, respectively. V_4 was pulsed to -1.9 kV at the time of data acquisition. As shown in FIG. 12, the Insulin had a peak width indicated by arrows 300 and 302 of approximately 160 ns. As shown in FIG. 13, the Cytochrome-c had a peak width, indicated by arrows 304 and 306, of approximately 160 ns. As shown in FIG. 14, the Lysozyme had a peak width, indicated by arrows 308 and 310, of approximately 340 ns. Finally, as shown in FIG. 15, the Trypsinogen had a peak width, indicated by arrows 312 and 314, of approximately 340 ns.

Referring now to FIGS. 16 and 19, ion intensity versus time-of-flight data were again generated for the Insulin sample, Cytochrome-c sample, Lysozyme sample, and Trypsinogen sample, respectively, using MALDI techniques wherein spatial-velocity correlation focusing, in accordance with the present invention, was performed to reduce ion peak broadening.

In this particular case, the distances d_1 , d_2 , L and d_3 were 12.05 mm, 13.34 mm, 210.81 mm and 27.26 mm, respectively.

For the Insulin sample, the algorithm of FIG. 11 was employed to determine optimal operating conditions for TOFMS 100. As a result, plate 102 and grid 106 were initially set at 15 kV, and after a delay time of 2.25 microseconds, plate 102 was pulsed from 15 kV to 16.8 kV. Plate 113 was maintained at 12.06 kV. As a variation on the geometry of the detector 116, a grid was placed at the dotted line 119 shown in FIG. 6, and was held at ground potential. The distance between the grid 115 and the new grid 119 was 22.06 mm. The detector 116 was pulsed from -1.4 kV to -1.9 kV a predetermined time period after the pulsing of plate 102. The front surface 117 of the detector 116 was located at a distance of 5.2 mm from grid 119. As shown in FIG. 16, the Insulin sample had a peak width, indicated by arrows 400 and 402, of approximately 12 ns. The improvement over the 160 ns peak of FIG. 12 represents approximately a 93% peak width reduction and is due to the spatial-velocity correlation focusing techniques of the present invention.

For the Cytochrome-c sample, the algorithm of FIG. 11 was similarly employed to determine optimal operating conditions for TOFMS 100. As a result, plate 102 and grid 106 were initially set at 15 kV, and after a delay time of 6.9 microseconds, plate 102 was pulsed from 15 kV to 16.437 kV. Grid 113 was maintained at 12.5 kV. As shown in FIG. 17, the Cytochrome-c sample had a peak width, indicated by arrows 404 and 406, of approximately 12 ns. The improvement over the 160 ns peak of FIG. 13 represents approximately a 93% peak width reduction and is due to the spatial-velocity correlation focusing techniques of the present invention.

For the Lysozyme sample, the algorithm of FIG. 11 was similarly employed to determine optimal TOFMS 100 conditions. As a result, plate 102 and grid 106 were initially set at 15 kV, and after a delay time of 5.6 microseconds, plate 102 was pulsed from 15 kV to 16.586 kV. Grid 113 was maintained at 11.5 kV and the detector 116 voltage was operated identically as with the Cytochrome-c sample. As shown in FIG. 18, the Lysozyme sample had a peak width, indicated by arrows 408 and 410, of approximately 12 ns.

The improvement over the 340 ns peak width of FIG. 14 represents approximately a 96% peak width reduction and is due to the spatial-velocity correlation focusing techniques of the present invention.

For the Trypsinogen sample, the algorithm of FIG. 11 was once more employed to determine optimal TOFMS 100 conditions. As a result, plate 102 and grid 106 were initially set at 15 kV, and after a delay time of 6.7 microseconds, plate 102 was pulsed from 15 kV to 16.981 kV. Grid 113 was maintained at 10.5 kV and the detector 116 voltage was operated identically as with the previous two samples. As shown in FIG. 19, the Trypsinogen sample also had a peak width, indicated by arrows 412 and 414, of approximately 12 ns. As with the previous sample, the improvement over the 340 ns peak width of FIG. 15 represents approximately a 96% peak width reduction and is due to the spatial-velocity correlation focusing techniques of the present invention.

In addition to the fact that the method of space velocity correlation focusing enables simultaneous ion spatial and velocity focusing, two additional advantages over the traditional MALDI approach of using a high DC ion drawout field accrue. First, in a high ion drawout field, variations in sample morphology, that correspond to variations in the locations at which ions are produced, and likewise to variations in electrostatic potential at these points of formation, lead to significant variations in ion time-of-flight. Since with space velocity correlation focusing, drawout electric fields are smaller, variations in electrostatic potential caused by variations in ion formation locations are smaller. This, in conjunction with the fact that ion times of flight are spatially focussed, leads to correspondingly smaller ion flight time variations.

Second, in a DC ion drawout field, as in the traditional MALDI approach, variations in ion formation time in the source region lead directly to variations in measured ion flight times. However, with pulsed ion drawout, ion flight time is measured with respect to the onset of the ion drawout pulse. Variations in ion formation time (that occur preceding the drawout pulse) lead to variations in ion position in the source region at the time of the ion drawout pulse that are spatially focussed. Consequently, observed ion flight time variations can be significantly smaller than variations in ion formation time.

While the invention has been illustrated and described in detail in the drawings and foregoing description, the same is to be considered as illustrative and not restrictive in character, it being understood that only the preferred embodiment has been shown and described and that all changes and modifications that come within the spirit of the invention are desired to be protected. For example, the term "ion" in the description of the preferred embodiment applies equally to ions directly desorbed from a sample surface and to neutrals desorbed from a sample surface and subsequently ionized. Furthermore, a timed electric field E_1 has been disclosed as being generated by applying a voltage pulse at plate 102 such that the voltage at plate 102 is greater than the voltage at grid 106 for the duration of the pulse. Alternatively, the electric field E_1 may be established by varying the potential applied to grid 106. Finally, the spatial-velocity correlation focusing techniques described herein are applicable to any time-of-flight instruments wherein ion times-of-flight are used to determine mass to charge ratio and the sample source geometry indicates a functional relationship between initial ion position and initial ion velocity. Thus, the present invention may be used to improve the mass resolution of reflectron TOFMS systems, or systems employing non-linear magnetic or electric fields, for

example. Further, applications such as DNA and protein sequencing, for example, can be enhanced using the techniques described herein.

These examples are illustrative of the spirit of the present invention and other variations of the disclosed embodiments are contemplated.

What is claimed is:

1. A method of operating a time-of-flight mass spectrometer, the spectrometer having a first region including a sample source disposed therein, and an ion detector remote from the first region, the method comprising the steps of:

establishing a non-zero field within the first region of the spectrometer;

generating ions from the sample source within the first region;

establishing an ion accelerating field within the first region after establishing said non-zero field therein, said ion accelerating field accelerating said ions generated within the first region toward the ion detector; and

detecting said accelerated ions at the ion detector and determining therefrom mass to charge ratios of said accelerated ions.

2. The method of claim 1 wherein the accelerating step occurs a predetermined time period after the generating step.

3. The method of claim 2 wherein the detecting step includes the steps of:

measuring time-of-flight of the generated ions as elapsed time between acceleration of the generated ions and arrival times of the various accelerated ions at the ion detector; and

determining mass-to-charge ratios of the various accelerated ions from the corresponding time-of-flight measurements.

4. The method of claim 1 wherein said non-zero field is a non-zero electric field.

5. A method of operating a time-of-flight mass spectrometer to minimize deleterious effects of distributions in initial ion position and initial ion velocity on the ion mass resolution of the spectrometer, said spectrometer including a first region for generating ions from a sample source disposed therein and an ion detector remote from the first region, the method comprising the steps of:

determining an equation for the time-of-flight of said ions generated within the first region to the detector, said equation being a function of a set of ion variables including initial position distribution and initial velocity distribution of said ions generated within the first region, said equation further being a function of a set of spectrometer variables including a time delay between generation of said ions within the first region and application of an ion accelerating electric field within the first region for accelerating said ions generated therein toward the detector;

determining an optimum set of values for said spectrometer variables from said equation such that any decrease in mass resolution of the spectrometer due to effects of said ion variables thereon are minimized;

generating said ions from the sample source within the first region; and

establishing an ion accelerating electric field within the first region for accelerating said ions generated therein toward the ion detector in accordance with said optimum set of values for said spectrometer variables.

6. The method of claim 5 wherein the sample source and the detector define a distance therebetween and said ion accelerating electric field has an accelerating field strength associated therewith;

and wherein said set of spectrometer variables further includes either of the distance between the first region and the detector and the accelerating field strength. 5

7. The method of claim 5 further including the step of establishing a non-zero electric field within the first region prior to establishing said ion accelerating electric field 10 therein.

8. The method of claim 7 wherein the sample source and the detector define a distance therebetween, said ion accelerating electric field has an accelerating electric field strength associated therewith, and the non-zero electric field 15 has a non-zero electric field strength associated therewith;

and wherein said set of spectrometer variables further includes any of the distance between the first region and the detector, the accelerating electric field strength and the non-zero electric field strength.

9. The method of claim 5 wherein the ions are generated from the sample source within the first region via laser desorption.

10. The method of claim 5 wherein a derivative of said equation varies widely with respect to a range of initial ion positions and with respect to a range of initial ion velocities.

11. The method of claim 10 wherein the sample source and the detector define a distance therebetween and said ion accelerating electric field has an accelerating field strength associated therewith;

and wherein said set of spectrometer variables further includes either of the distance between the first region and the detector and the accelerating field strength.

12. The method of claim 11 further including the step of establishing a non-zero electric field within the first region prior to establishing said ion accelerating electric field therein.

* * * * *

1 13. A method of obtaining accurate molecular weights by matrix assisted laser
2 desorption/ionization time-of-flight mass spectrometry by delaying ion extraction long enough
3 for a plume of ions to dissipate such that substantially no energy loss is due to collisions, the
4 method comprising:

- 5 a) applying a potential to a sample holder;
- 6 b) applying a potential to a first element spaced apart from the sample holder which
7 is substantially equal to the potential on the sample holder;
- 8 c) ionizing a sample proximately disposed to the holder to form a cloud of ions with
9 a laser which generates a pulse of energy;
- 10 d) applying a second potential to either the sample holder or to the sample at a
11 predetermined time subsequent to steps a through c which:
 - 12 i) together with the potential on the first element, defines a second electric
13 field between the sample holder and the first element; and
 - 14 ii) extracts the ions after the predetermined time, wherein the predetermined
15 time is long enough to allow the cloud of ions to expand enough to
16 substantially eliminate the addition of excessive collisional energy to the
17 ions during ion extraction.

18
19 14. The method of claim 13 further comprising the step of measuring the time of flight to a
20 detector and calculating the mass-to-charge ratio from the time of flight measurement.

21
22 15. The method of claim 13 wherein the sample comprises a matrix substance which absorbs
23 radiation at a wavelength substantially corresponding to the pulse of energy, the matrix

1 facilitating desorption and ionization of molecules.

2
3 16. The method of claim 13 further comprising the step of applying a potential to a second
4 element spaced apart from the first element which, together with the potential on the first
5 element, defines an electric field between the first and second elements for accelerating the ions.

6
7 17. The method of claim 13 wherein the sample comprises at least one compound of
8 biological interest selected from the group consisting of DNA, RNA, polynucleotides and
9 synthetic variants thereof.

10
11 18. The method of claim 13 wherein the sample comprises at least one biomolecule selected
12 from the group consisting of peptides, proteins, PNA, carbohydrates, glycoconjugates and
13 glycoproteins.

14
15 / 19. A method of improving mass resolution in time-of-flight mass spectrometry by
16 compensating for an initial velocity distribution of ions to at least second order comprising:

- 17 a) applying a potential to a sample holder;
18 b) applying a potential to a first element spaced apart from the sample holder which,
19 together with a potential on the sample holder defines an electric field between the
20 sample holder and the first element;
21 c) ionizing a sample proximately disposed to the holder to form sample ions;
22 d) applying a second potential to either the sample holder or the first element at a
23 predetermined time subsequent to steps a) and c) which together with the potential

1 on the first element, defines a second electric field between the sample holder and
2 the first element, and which extracts the ions from the first element after the
3 predetermined time; and

4 e) energizing an ion reflector spaced apart from the first element.

5 wherein the first and second electric fields and the predetermined time are chosen such
6 that a flight time of extracted ions of like mass-to-charge ratio from the reflector to a detector
7 will be independent to second order of the initial velocity.

8
9 20. The method of claim 19 wherein the first electric field in step b) is zero.

10
11 21. The method of claim 19 wherein the first electric field in step b) is nonzero and is
12 operative spatially to separate ions by their mass prior to ion extraction.

13
14 22. The method of claim 19 wherein the potential on the first element with respect to the
15 potential of the sample holder is more positive for measuring positive ions and more negative for
16 measuring negative ions prior to ion extraction.

17
18 23. The method of claim 19 further comprising the step of applying a potential to a second
19 element spaced between the first element and the reflector which creates an electric field between
20 the first and second elements to accelerate the ions.

21
22 24. The method of claim 19 wherein the sample is ionized by a laser producing a pulse of
23 energy.

25. The method of claim 19 wherein the sample comprises a matrix substance which absorbs radiation at a wavelength substantially corresponding to the pulse of energy, the matrix facilitating desorption and ionization of molecules.

[45] Date of Patent: Jan. 27, 1998

4,694,167	9/1987	Payne et al.	250/287
5,160,840	11/1992	Vestal	250/287
5,504,326	4/1996	Reilly et al.	250/287
5,510,613	4/1996	Reilly et al.	250/287

Attorney, Agent, or Firm—Woodard, Emhardt, Naughton,
Moriarty & McNett

[57] **ABSTRACT**

An apparatus and method for minimizing ion peak width measurements in a time-of-flight mass spectrometer to thereby minimize the effects of initial ion position distributions and initial ion velocity distributions on the mass resolution of the spectrometer are provided. Where the ion source and ion generation geometries indicate a functional relationship between the initial ion position and initial ion velocity, this relationship is substituted into the time-of-flight equation and the instrument parameters are thereafter optimized to achieve minimization of ion peak width broadening. Experimental results using MALDI indicate reductions in ion peak widths of up to 96% over those observed with traditional MALDI techniques.

12 Claims, 10 Drawing Sheets

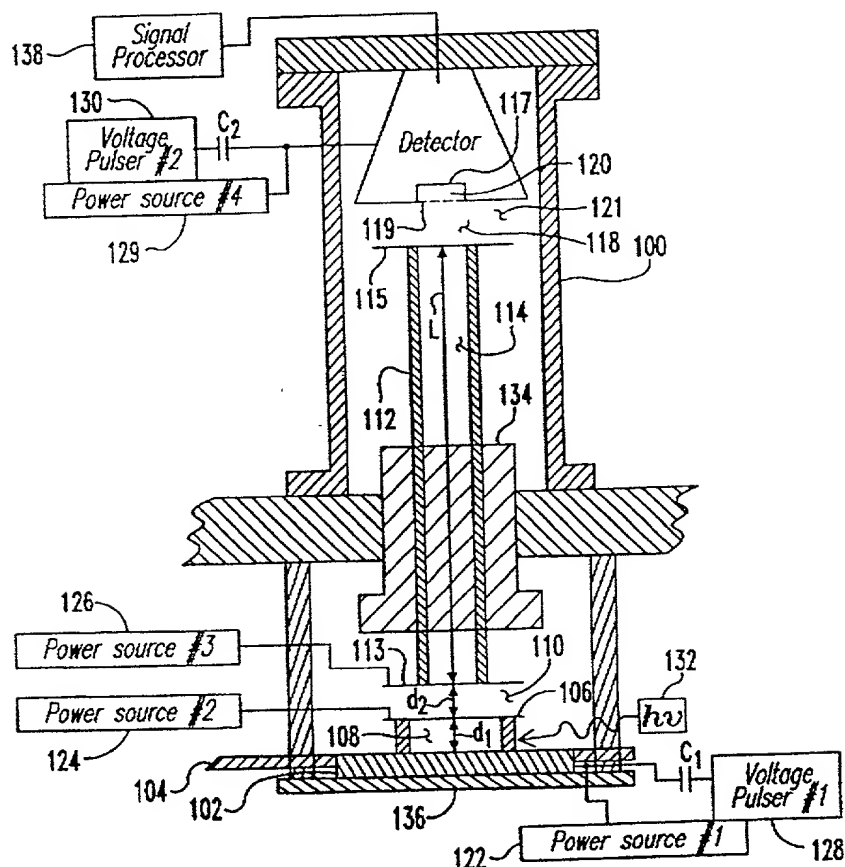


Fig. 1
(Prior Art)

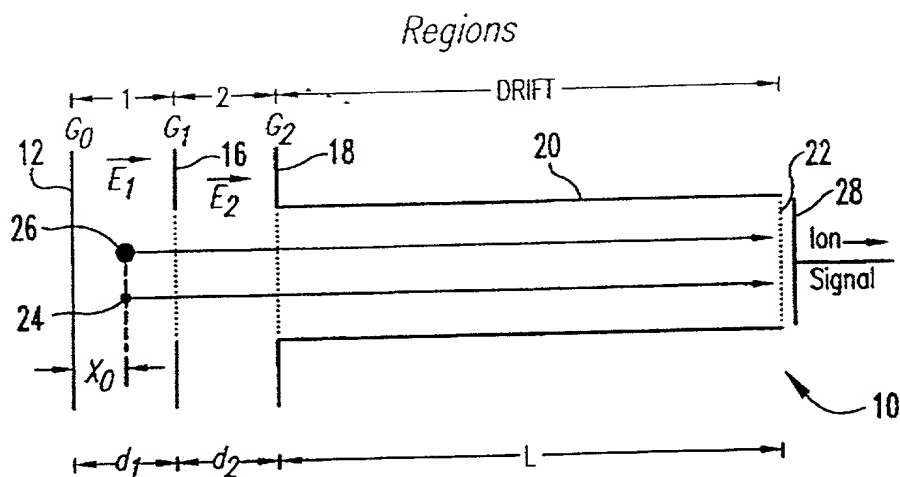


Fig. 2
(Prior Art)

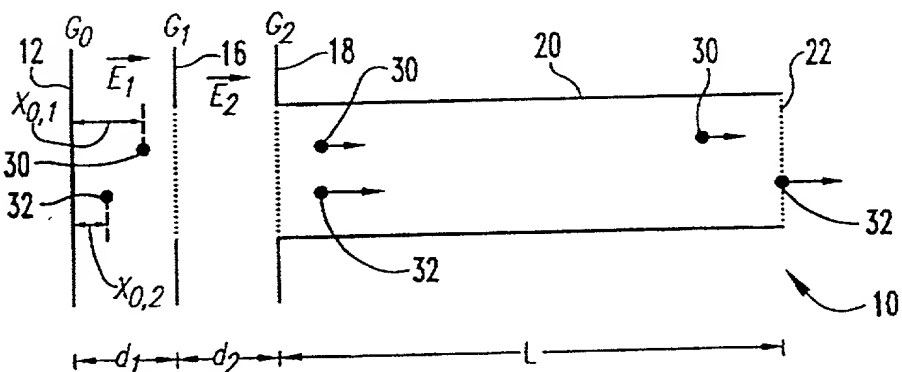
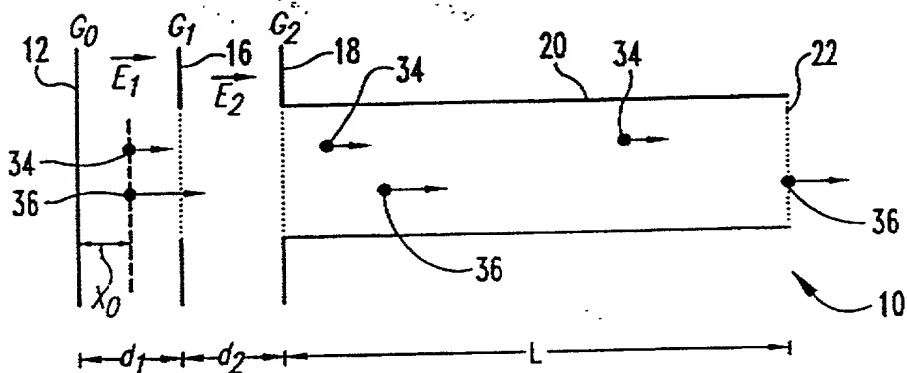


Fig. 3
(Prior Art)



[illegible]

Diagram illustrating a beam splitter 11. An incident beam 12 enters from the left, passes through a glass plate 16, and is split into two beams 20' and 28. The beams are recombined at a second glass plate 22. The distance from the first plate to the second plate is L' . The distance from the incident beam to the first plate is d_1 , and the distance from the first plate to the second plate is d_2 .

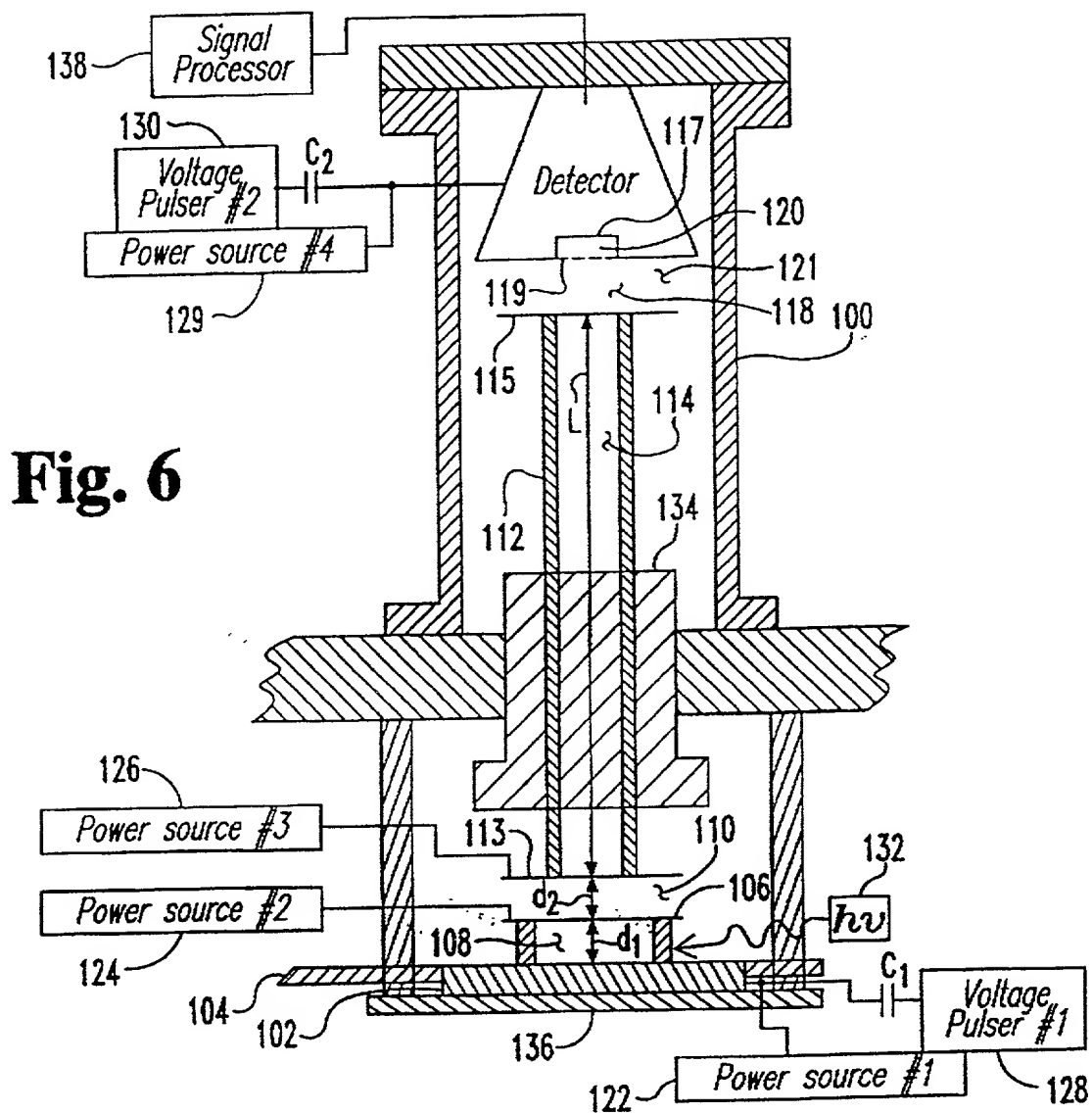


Fig. 7

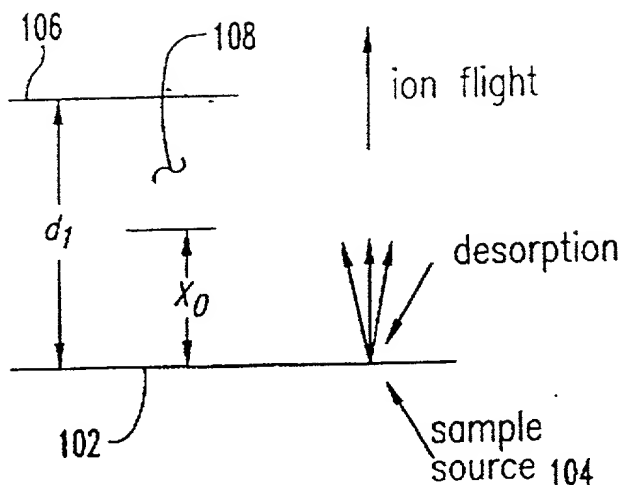


Fig. 8

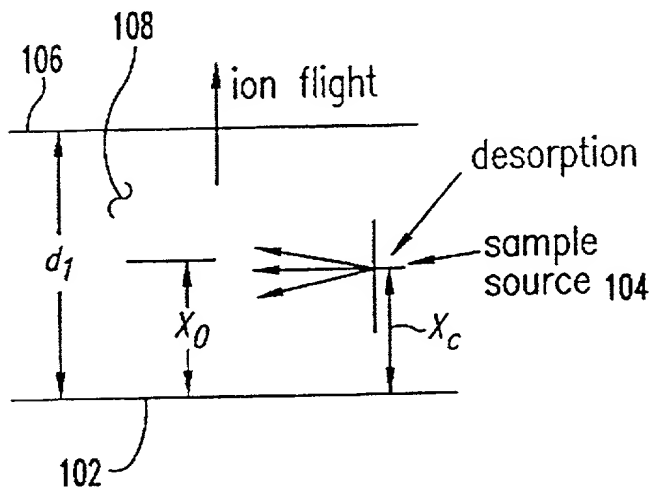


Fig. 9

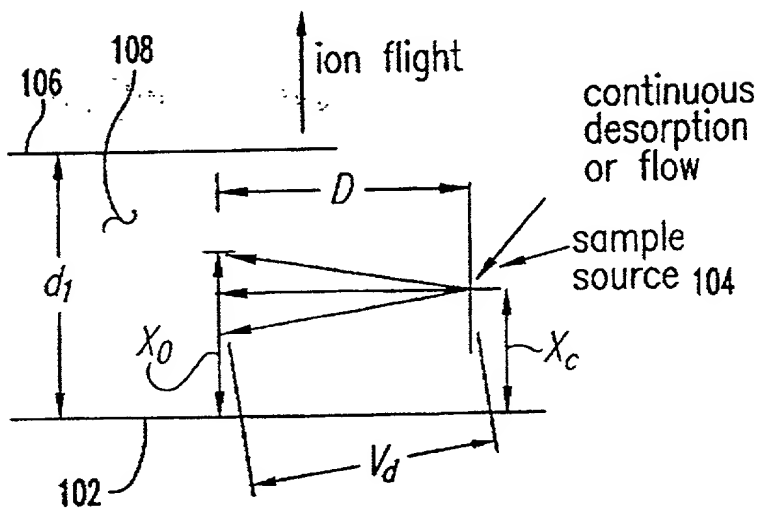
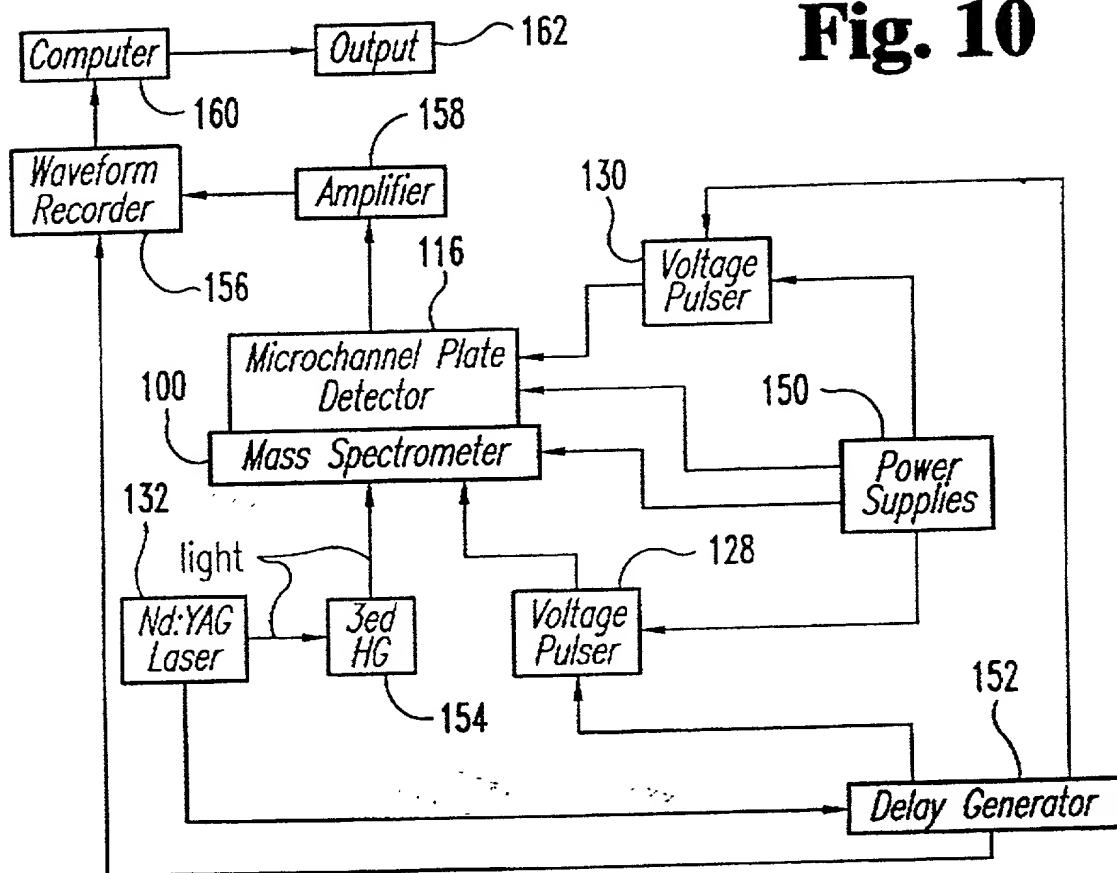
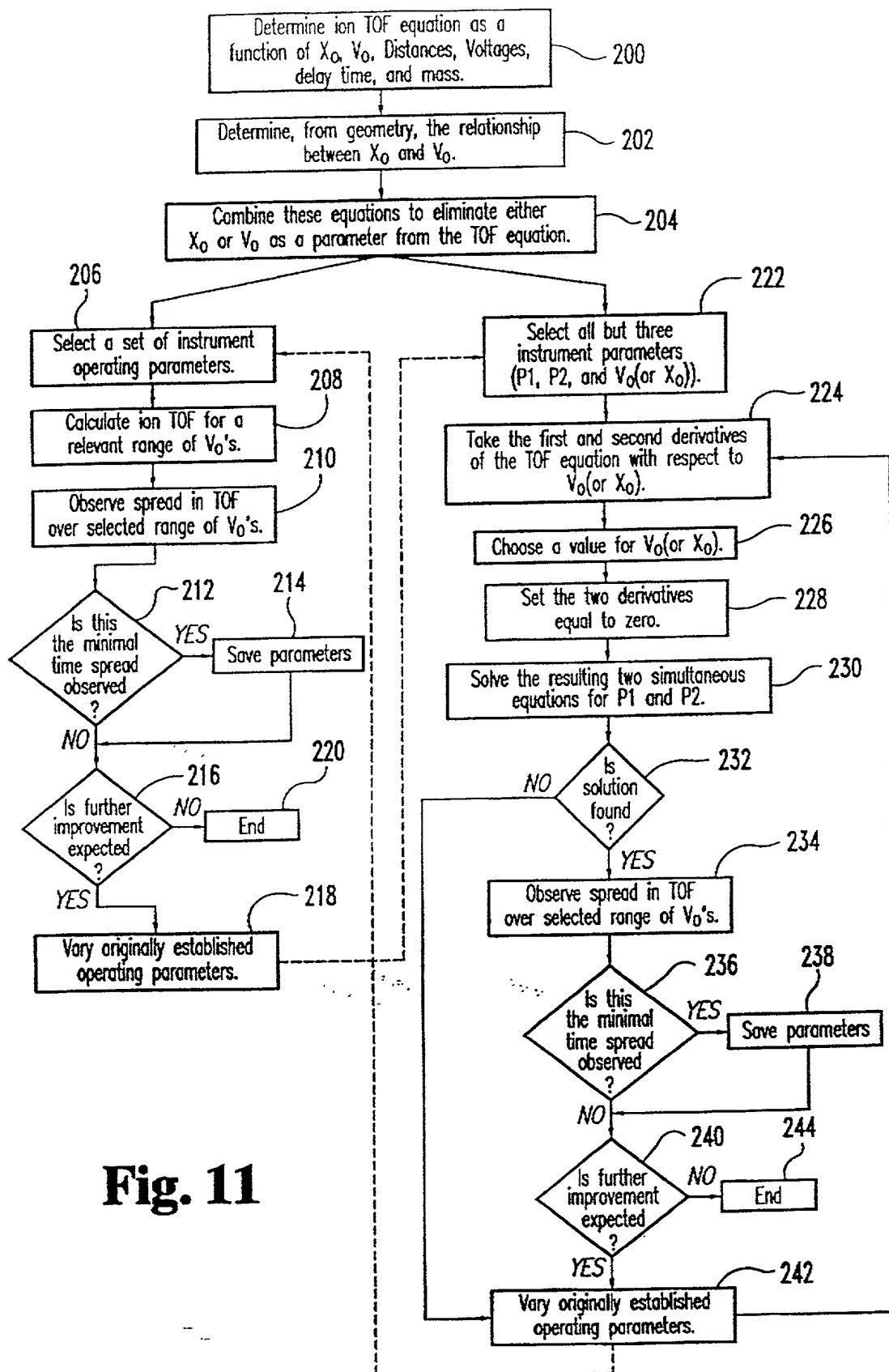
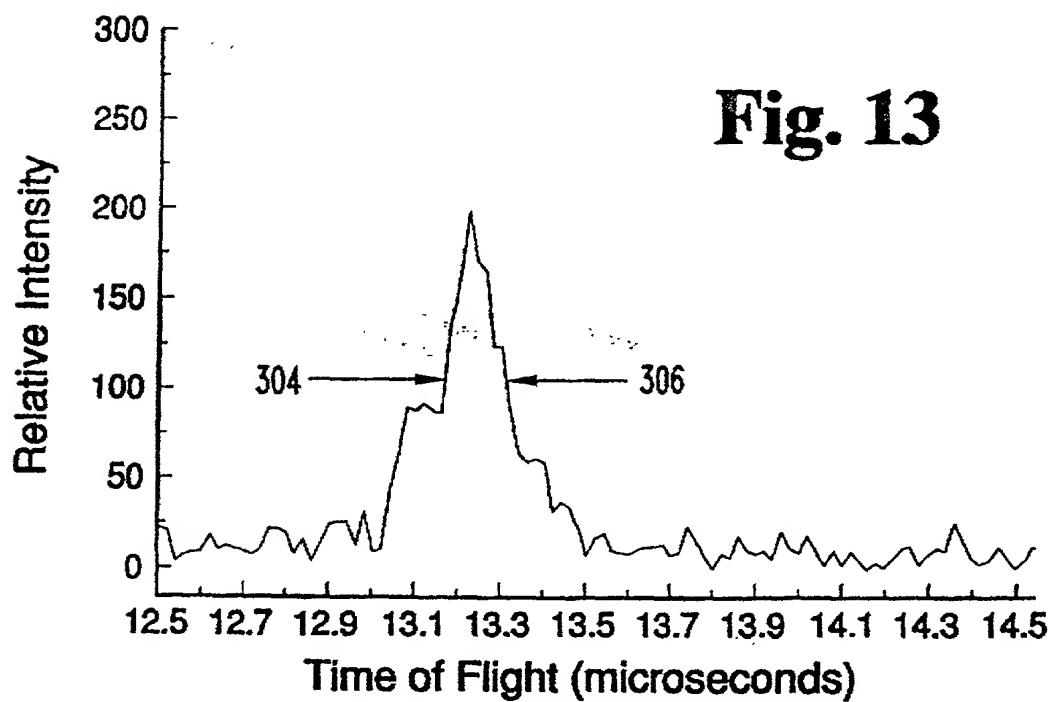
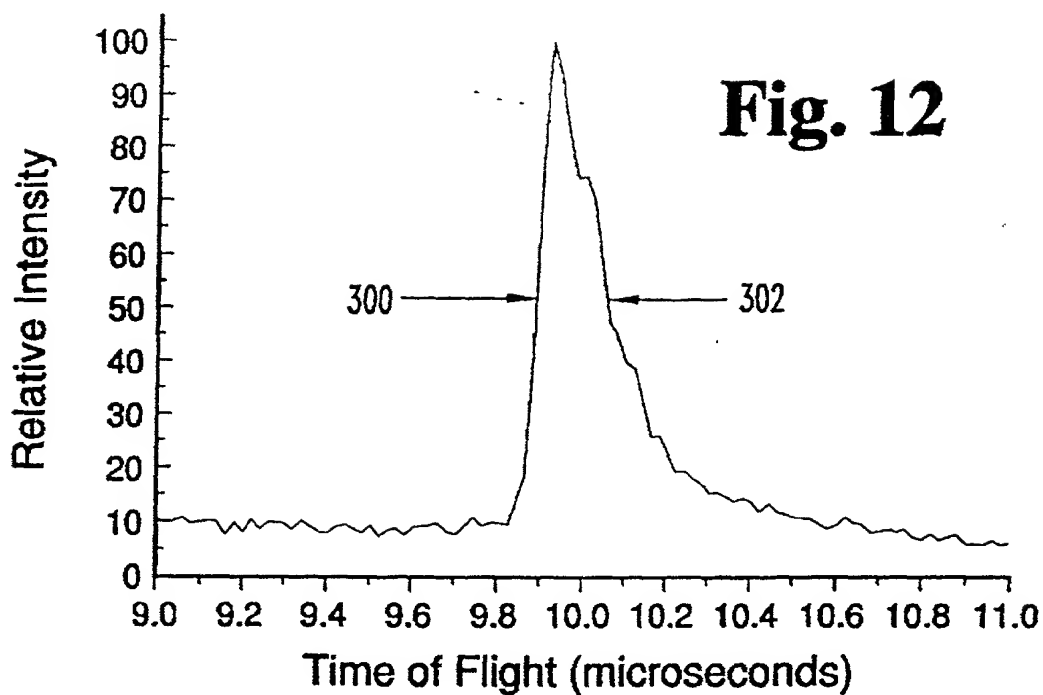
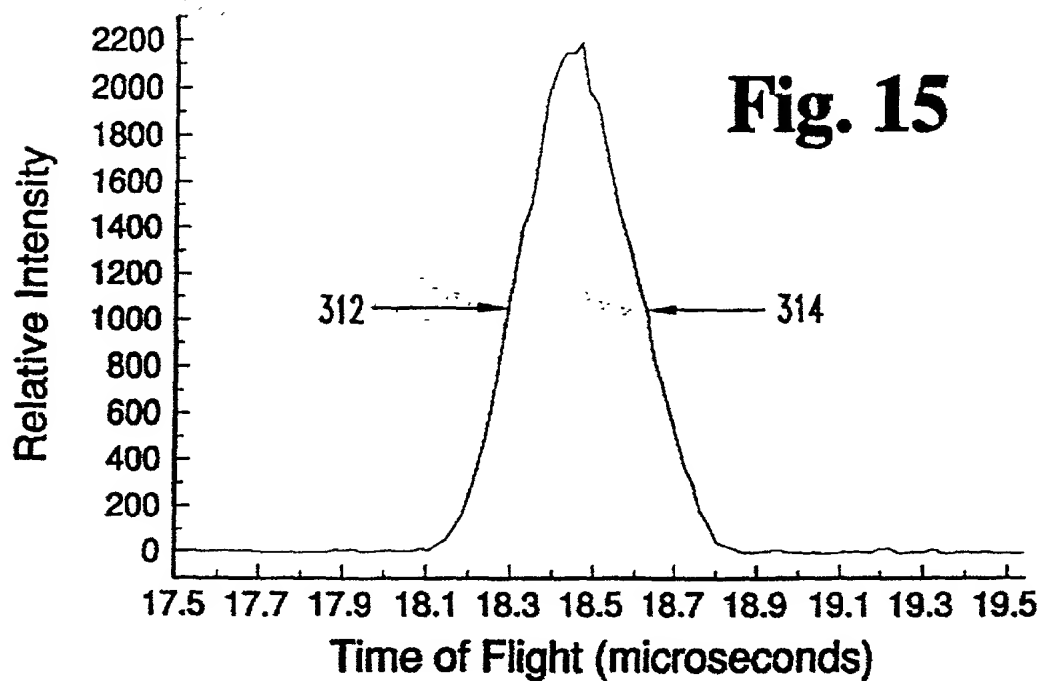
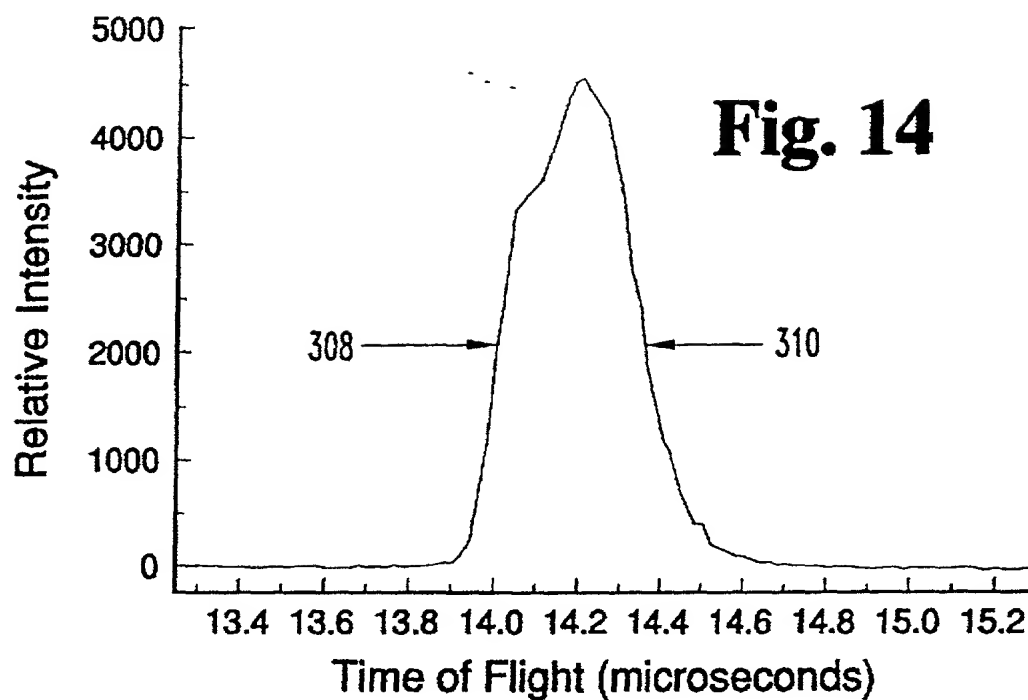
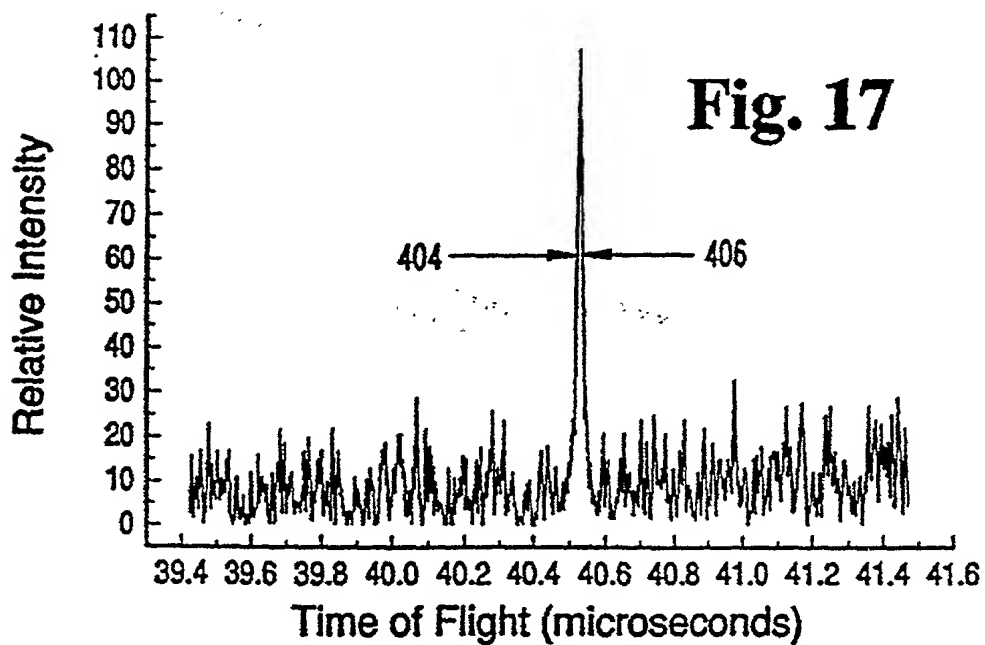
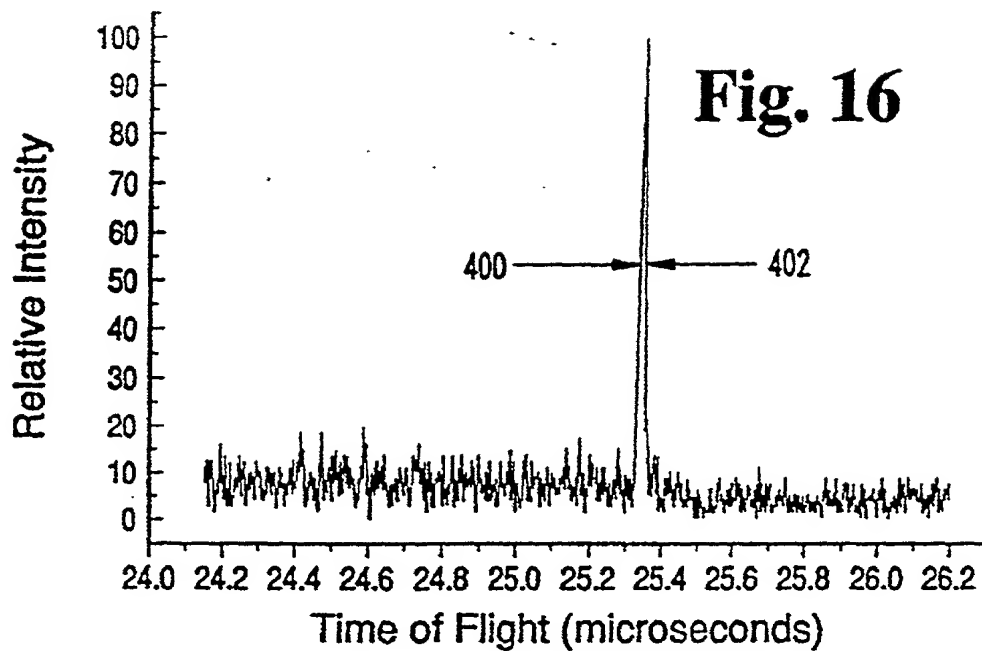


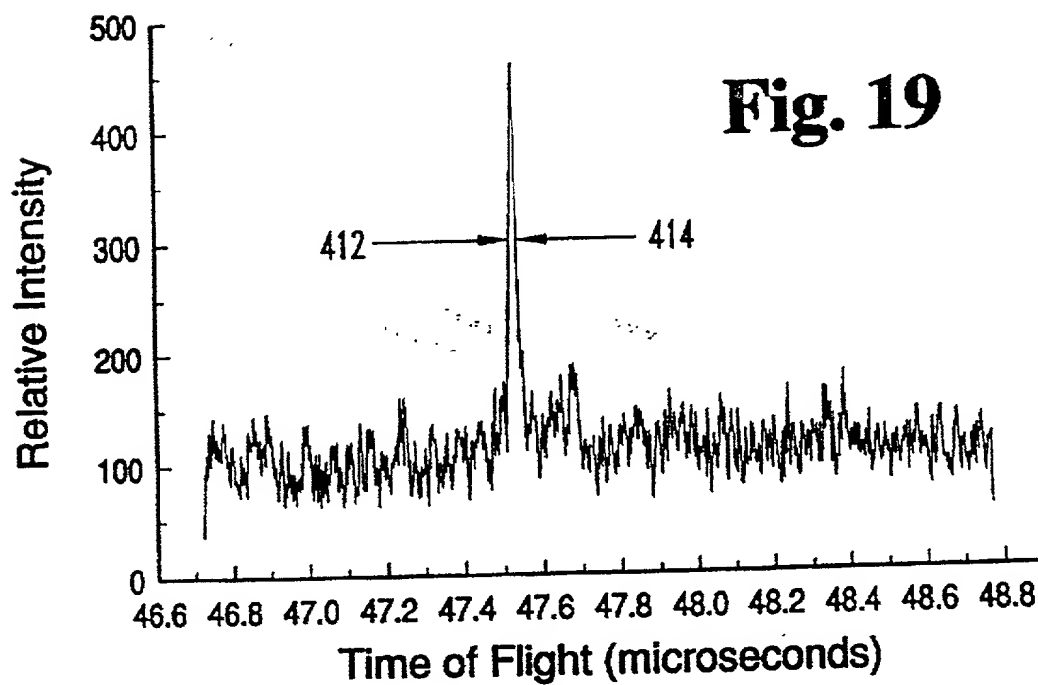
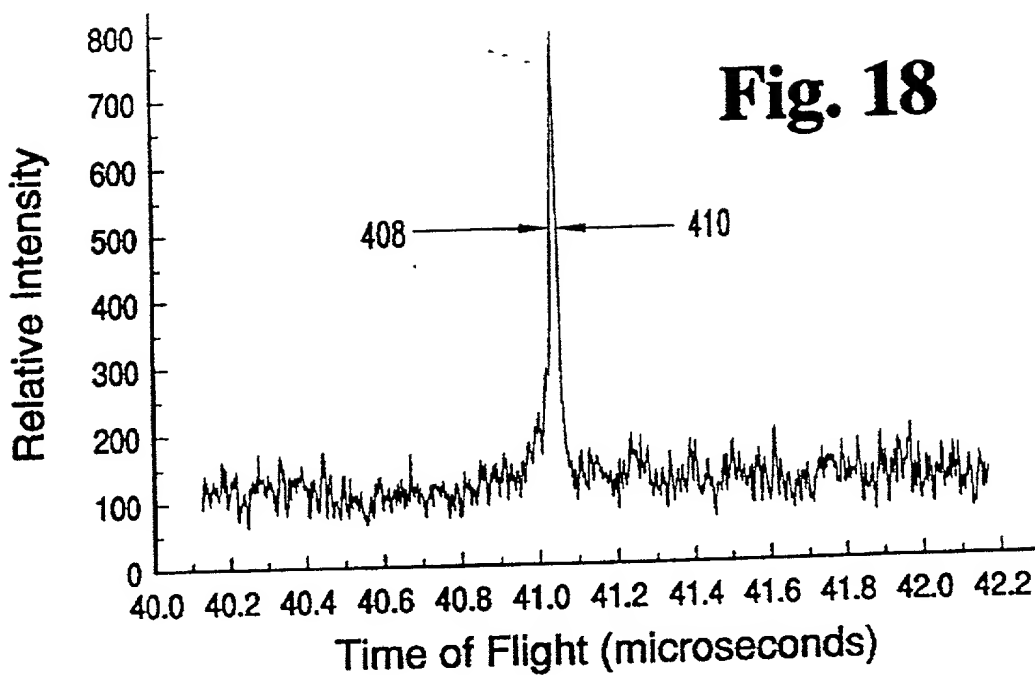
Fig. 10

**Fig. 11**









Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it displays a valid OMB control number.

REISSUE APPLICATION DECLARATION BY THE INVENTOR

Docket Number (Optional)

140-035

As a below named inventor, I hereby declare that:

My residence, post office address and citizenship are stated below next to my name.

I believe I am the original, first and sole inventor (if only one name is listed below) or an original, first and joint inventor (if plural names are listed below) of the subject matter which is described and claimed in patent number 5,712,479, granted January 27, 1998, and for which a reissue patent is sought on the invention entitled SPATIAL-VELOCITY CORRELATION FOCUSING IN TIME-OF-FLIGHT MASS SPECTROMETRY,
the specification of which

☒ is attached hereto.

☐ was filed on _____ as reissue application number ____ / _____
and was amended on _____
(If applicable)

I have reviewed and understand the contents of the above identified specification, including the claims, as amended by any amendment referred to above.

I acknowledge the duty to disclose information which is material to patentability as defined in 37 CFR 1.56.

I verily believe the original patent to be wholly or partly inoperative or invalid, for the reasons described below. (Check all boxes that apply.)

☐ by reason of a defective specification or drawing.

☒ by reason of the patentee claiming more or less than he had the right to claim in the patent.

☐ by reason of other errors.

At least one error upon which reissue is based is described as follows:

Subject matter described in the specification as originally filed was mistakenly omitted from the claims.

New claims 13 through 25, which have been copied from Vestal et al. U.S. Patent No. 5,760,393, which issued on June 2, 1998, are also fully supported by the specification as originally filed.

[Page 1 of 2]

Burden Hour Statement: This form is estimated to take 0.5 hours to complete. Time will vary depending upon the needs of the individual case. Any comments on the amount of time you are required to complete this form should be sent to the Chief Information Officer, Patent and Trademark Office, Washington, DC 20231. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Assistant Commissioner for Patents, Washington, DC 20231.

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it displays a valid OMB control number.

(REISSUE APPLICATION DECLARATION BY THE INVENTOR, page 2)

Docket Number (Optional)
140-035

All errors corrected in this reissue application arose without any deceptive intention on the part of the applicant. As a named inventor, I hereby appoint the following attorney(s) and/or agent(s) to prosecute this application and transact all business in the Patent and Trademark Office connected therewith.

Name(s) Registration Number

John W. Olivo Jr., Esq. 35,634

John F. Ward, Esq. 33,811

Correspondence Address: Direct all communications about the application to:

☐ Customer Number

OR

Type Customer Number here

Place Customer Number Bar
Code Label here

<input checked="" type="checkbox"/> Firm or Individual Name	Ward & Olivo				
Address	708 Third Avenue				
Address					
City	New York	State	NY	ZIP	10017
Country	USA				
Telephone	(212) 697-6262	Fax	(212) 972-5866		

I hereby declare that all statements made herein of my own knowledge are true and that all statements made on information and belief are believed to be true; and further that these statements were made with the knowledge that willful false statements and the like so made are punishable by fine and imprisonment, or both, under 18 U.S.C. 1001, and that such willful false statements may jeopardize the validity of the application, any patent issuing thereon, or any patent to which this declaration is directed.

Full name of sole or first inventor (given name, family name)

James P. Reilly

Inventor's signature

Residence

Date

Post Office Address

Citizenship

Full name of second joint inventor (given name, family name)

Steven M. Colby

Inventor's signature

Date

Residence

Citizenship

Post Office Address

Full name of third joint inventor (given name, family name)

Timothy B. King

Inventor's signature

Date

Residence

Citizenship

Post Office Address

☐ Additional joint inventors are named on separately numbered sheets attached hereto.

***** BIBLIOGRAPHIC DATA DISPLAY *****

06/14/99 06:46

APPL#: 08/566140 ATTY DOCK NO: CORRESPONDENCE ADDRESS: CUSTOMER NO. 000000
 28: IU-45-CON JEFFREY A MICHAEL
 FILD: 12/01/95 WOODARD EMHARDT NAUGHTON
 PATNO: 5712479 MORIARTY & MCNETT
 ISSD: 01/27/98 GAU: 2878 111 MONUMENT CIRCLE SUITE 3700
 CITY: INDIANAPOLIS
 ST/CO CODE: IN ZIP/CD: 46204
 FAX: () - TEL: () -

EMAIL

DOCK CL/SC: 250/282.000 FOR PR: N
 CURR CL/SC: 250/282.000 PARENT: N

TITLE:

SPATIAL-VELOCITY CORRELATION FOCUSING IN TIME-OF-FLIGHT MASS
 SPECTROMETRY

INVENTORS:

01 REILLY JAMES P. IN
 (AUTH): (CITY,ST/CO CODE): BLOOMINGTON
 02 COLBY STEVEN M. IN
 BLOOMINGTON

PUSH SEND KEY TO DISPLAY MORE APPLICANTS

***** BIBLIOGRAPHIC DATA DISPLAY *****

06/14/99 06:46

APPL#: 08/566140 ATTY DOCK NO: CORRESPONDENCE ADDRESS: CUSTOMER NO. 000000
 28: IU-45-CON JEFFREY A MICHAEL
 FILD: 12/01/95 WOODARD EMHARDT NAUGHTON
 PATNO: 5712479 MORIARTY & MCNETT
 ISSD: 01/27/98 GAU: 2878 111 MONUMENT CIRCLE SUITE 3700
 CITY: INDIANAPOLIS
 ST/CO CODE: IN ZIP/CD: 46204
 FAX: () - TEL: () -

EMAIL

DOCK CL/SC: 250/282.000 FOR PR: N
 CURR CL/SC: 250/282.000 PARENT: N

TITLE:

SPATIAL-VELOCITY CORRELATION FOCUSING IN TIME-OF-FLIGHT MASS
 SPECTROMETRY

INVENTORS:

03 KING TIMOTHY B. IN
 (AUTH): (CITY,ST/CO CODE): BLOOMINGTON

END OF DISPLAY

PATENT NUMBER: 5712479 ISSUE DATE: 01/27/98
 SERIAL NUMBER: 08/566140 FILING DATE: 12/01/95
 TITLE: SPATIAL-VELOCITY CORRELATION FOCUSING IN TIME-OF-FLIGHT MASS
 SPECTROMETRY

APPLICANT: REILLY, JAMES P. ; COLBY, STEVEN M.
KING, TIMOTHY B.

REEL: 8861 FRAME: 0293 MAILROOM DT: 12/22/97 NEW APP FIL RCPT DT: 00/00/00
DATE IN ASSIGNMENTS: 01/08/98 DT MAILED: 02/13/98
DATE RECORDED: 12/22/97 NUMBER OF PAGES: 022

ASSIGNOR: INDIANA UNIVERSITY FOUNDATION

EXC DATE: 06/30/97
ASSIGNEE: ADVANCED RESEARCH & TECHNOLOGY INSTITUTE
501 NORTH MORTON STREET, SUITE 111
BLOOMINGTON, INDIANA 47404

BRIEF:

ASSIGNMENT OF ASSIGNOR'S INTEREST (SEE DOCUMENT FOR DETAILS).

06/14/99 06:47

YOU HAVE MORE SCREENS,PRESS THE ASSNR KEYS & SEND FOR NEXT SCREEN
RETURN ADDRESS: LOCKE REYNOLDS BOYD & WEISELL
A. JAMES RICHARDSON, ESQ.
1000 CAPITAL CENTER SOUTH
201 NORTH ILLINOIS ST.
INDIANAPOLIS, IN 46204

NO MORE INFORMATION FOR THIS PATENT NUMBER 06/14/99 06:47

06/14/99 06:47